



PTO/SB/08a/b (08-03)
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Substitute for form 1449A/B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)				Complete if Known	
				Application Number	10/665,757 (Conf. No. 6828)
				Filing Date	September 19, 2003
				First Named Inventor	Glenn J. Leedy
				Art Unit	2822
				Examiner Name	Pamela E. Perkins
Sheet	1	of	3	Attorney Docket Number	ELM-1 Cont.9

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
PSP		US 4,604,162	08-05-1986	Sobczak	_____
		US 4,849,857	07-18-1989	Butt et al.	_____
		US 4,928,058	05-22-1990	Williamson	_____
		US 4,990,462	02-05-1991	Sliwa.	_____
		US 5,110,712	05-05-1992	Kessler et al.	_____
		US 5,119,164	06-02-1992	Sliwa et al.	_____
		US 5,284,804	02-08-1994	Moslehi	_____
		US 5,480,842	01-02-1996	Clifton et al.	_____
		US 5,470,693	11-28-1995	Sachdev et al.	_____
		US 5,733,814	03-31-1998	Flesher et al.	_____
PSP		US Re 37,637	04-09-2002	Clifton et al.	_____

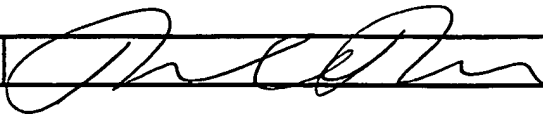
FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
PSP		EP 0 201 380 B1	12-17-1986	Fairchild Semiconductor Corporation		
		EP 0 224 418 B1	06-03-1987	Fujitsu Limited		
		EP 0 419 898 B1	04-03-1991	Siemens Aktiengesellschaft		
		EP 0 455 455 B1	11-06-1991	AT&T Corp.		
		EP 0 487 302 B1	05-27-1992	Shin-ETSU Handotai Company Limited		
		EP 0 503 816 B1	09-16-1992	Shin-ETSU Handotai Company Limited		
		EP 0 518 774 B1	12-16-1992	France Telecom		
		EP 0 526 551 B1	02-10-1993	The Commonwealth of Australia		
		EP 0 554 063 B1	08-04-1993	Canon Kabushiki Kaisha		
		EP 0 555 252 B1	08-18-1993	Fraunhofer-Gesellschaft Zur Förderung Der Angewandten Forschung E.V..		
PSP		WO 1989 010255	11-02-1989	3D Systems Inc.		
PSP		WO 1990 009093	08-23-1990	Polythetics Inc.		
PSP		WO 1992 017901	10-15-1992	Integrated System Assemblies Corporation		

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NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
REP		Jones, R.E., Jr. "An evaluation of methods for passivating silicon integrated circuits"; April 1972; pp. 23-8	
		Svechnikov, S.V.; Kobylitskaya, M.F.; Kimarskii, V.I.; Kaufman, A.P.; Kuzovlev, Yu. I.; Cherepov, Ye. I.; Fomin, B.I.; "A switching plate with aluminum membrane crossings of conductors"; 1972	
		Sun, R.C.; Tisone, T.C.; Cruzan, P.D.; "Internal stresses and resistivity of low-voltage sputtered tungsten films (microelectronic cct. conductor)"; March 1973; pp. 1009-16	
		Wade, T.E.; "Low temperature double-exposed polyimide/oxide dielectric for VLSI multilevel metal interconnection"; 1982; pp. 516-19	
		Boyer, P.K.; Collins, G.J.; Moore, C.A.; Ritchie, W.K.; Roche, G. A.; Solanski, R. (A); Tang, C.C.; "Microelectronic thin film deposition by ultraviolet laser photolysis MONOGRAPH TITLE - Laser processing of semiconductor devices"; 1983; pp. 120-126	
		Boyer, P.K.; Moore, C.A.; Solanki, R.; Ritchie, W.K.; Roche, G.A.; Collins, G.J.; "Laser photolytic deposition of thin films"; 1983; pp. 119-27	
		Chen, Y.S.; Fatemi, H.; "Stress measurements on multilevel thin film dielectric layers used in Si integrated circuits"; May-June 1986; pp. 645-9	
		Salazar, M.; Wilkins, C.W., Jr.; Ryan, V.W.; Wang, T.T.; "Low stress films of cyclized polybutadiene dielectrics by vacuum annealing"; Oct. 21-22, 1986; pp. 96-102	
		Townsend, P.H.; Huggins, R.A.; "Stresses in borophosphosilicate glass films during thermal cycling"; Oct. 21-22, 1986; pp. 134-41	
		Pai, Pei-Lin; "Multilevel Interconnection Technologies--A Framework And Examples"; 1987; pp. 1871	
		Pei-lin Pai; Chetty, A.; Roat, R.; Cox, N.; Chiu Ting; "Material characteristics of spin-on glasses for interlayer dielectric applications"; November 1987, pp. 2829-34	
		Allen, Mark G.; Senturia, Stephen D.; "Measurement of polyimide interlayer adhesion using microfabricated structures"; 1988; pp. 352-356	
		Chang, E.Y.; Cibuzar, G.T.; Pande, K.P.; "Passivation of GaAs FET's with PECVD silicon nitride films of different stress states"; September 1988; pp. 1412-18	
		Riley, P.E.; Shelley, A.; "Characterization of a spin-applied dielectric for use in multilevel metallization"; May 1988; pp. 1207-10	
		Tamura, H.; Nishikawa, T.; Wakino, K.; Sudo, T.; "Metalized MIC substrates using high K dielectric resonator materials"; October 1988; pp. 117-126	
		Kochugova, I.V.; Nikolaeva, L.V.; Vakser, N.M., (M.I. Kalinin Leningrad Polytechnic Institute (USSR); "Electrophysical investigation of thin-layered inorganic coatings"; 1989; pp. 826-828	
		Reche, J.J. H.; "Control of thin film materials properties used in high density multichip interconnect"; April 24-28, 1989; p. 494	

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		Maw, T.; Hopla, R.E.; "Properties of a photoimageable thin polyimide film"; Nov. 26-29, 1990; pp. 71-6	
		Draper, B. L.; Hill, T.A.; "Stress and stress relaxation in integrated circuit metals and dielectrics"; July-Aug. 1991; pp. 1956-62	
		Guckel, H.; "Surface micromachined pressure transducers"; 1991; pp. 133-146	
		Garino, T.J.; Harrington, H. M.; "Residual stress in PZT thin films and its effect on ferroelectric properties"; 1992; pp. 341-7	

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JEP		US 3,932,932	01-20-1976	Goodman	_____
		US 4,028,547	06-07-1977	Eisenberger	_____
		US 4,393,127	07-12-1983	Greschner et al.	_____
		US 4,528,072	07-09-1985	Kurosawa et al.	_____
		US 4,810,889	03-07-1989	Yokomatsu et al.	_____
		US 5,051,326	09-24-1991	Celler et al.	_____
		US 5,166,962	11-24-1992	Murooka et al.	_____
		US 5,169,805	12-08-1992	Mok et al.	_____
		US 5,188,706	02-23-1993	Hori et al.	_____
		US 5,432,999	07-18-1995	Capps et al.	_____
JEP		US 5,577,050	11-19-1996	Bair et al.	_____
		US 5,745,673	04-28-1998	Di Zenzo et al.	_____
		US 5,818,748	10-06-1998	Bertin et al.	_____

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